

**Joint Video Experts Team (JVET)
of ITU-T SG 16 WP 3 and ISO/IEC JTC 1/SC
29/WG 11**

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Title: EE2-4.4b and 4.4c: Combined Tests for ALF

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Abstract

There are 3 ALF-related EE tests during AC meeting cycle. In test 4.1, the additional fixed-filter for ALF is tested. In test 4.2, the residual based classifier for ALF is tested. In test 4.3, the ALF filter shape with more taps applied to fixed-filter result is tested. In this contribution, the results of ALF-related combined tests 4.4b and 4.4c are reported.

On top of ECM-8.0, simulation results of EE2-4.4a/4.4b/4.4c are reported as below:

4.4b:

AI: %, %, %, %, %.

RA: %, %, %, %, %.

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JVET-AD0222

<http://vexpertise.stbit.ru/documents/JVET-AD0222>

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ABSTRACT

MEETING NOTES

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JVET-AD0222_EE2_4_4_B.xlsm

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JVET-AD0222_EE2_4_4_C.xlsm

DOC

JVET-AD0222_v1.docx

FILE

TEST_44B_44C.patch

MEETING NOTES

external meeting notes

http://vexpertise.stbit.ru/meeting-notes/source/meeting_30_ad

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1 Summary

MEETING NOTES

JVET-AD0222 EE2-4.4b and 4.4c: Combined Tests for ALF [I. Jumakulyyev, N. Hu, Z. Zhi, V. Seregin, M. Karczewicz, H. Huang (Qualcomm), W. Yin, K. Zhang, L. Zhang (Bytedance)]

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